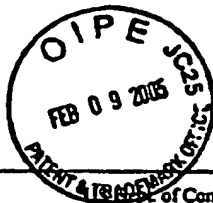


Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		APPLICATION NO. 10/625,617	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Tokuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP 2629	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
SL	1	5,463,279	10/31/1995	KHORMAEI			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
SL	2	JP-A-08-214048	09/17/1996	JAPAN	XX	XX	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER				DATE CONSIDERED			
Jean Desperance				7-19-06			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 12, 2006

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		U.S. Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		APPLICATION NO. 10/625,617	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANTS Tokuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP 2674	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
J.L.	1	JP 05-313195 (w/English-language translation)	11/26/1993	JAPAN			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER <i>John Key - ce</i>				DATE CONSIDERED <i>6-9-05</i>			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: February 9, 2005

Form PTO-1449  
(REV. 8-83)US Dept. of Commerce  
PATENT & TRADEMARK OFFICEATTY DOCKET NO.  
100629.03APPLICATION NO.  
10/625,617

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)  
Tokuroh OZAWA et al.FILING DATE  
July 24, 2003

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
J.L.	5,463,279	10/1995	KHORMAEI	315	169.03

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
J.L. JP-A-9-106887 (w/ Eng. Abstract)	04/1997	JAPAN	—	—
J.L. JP-A-10-12377 (w/ Eng. Abstract)	01/1998	JAPAN	—	—
J.L. EP 0 880 303 A1	11/1998	EUROPE	—	—
J.L. EP 0 849 721 A2	06/1998	EUROPE	—	—
J.L. EP 0 961 525 A1	12/1999	EUROPE	—	—

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


EXAMINER

*Jean Dupont*

DATE CONSIDERED

6-9-05

Examiner:

Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: November 6, 2003



Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		APPLICATION NO. 10/625,617	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Tokuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
J.L.	1	5,786,796	07/1998	TAKAYAMA et al.	345	76	
J.L.	2	5,986,632	11/1999	TAKAYAMA et al.	345	99	
J.L.	3	5,463,279	10/1995	KHORMAEI	315	169.3	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
J.L.	4	EP 0 653 741 A1	05/1995	EUROPE			
J.L.	5	JP 08-241057 (w/ English abstract)	09/1996	JAPAN			
J.L.	6	WO 96/06456	02/1996	WIPO			
J.L.	7	EP 0 112 700	07/1984	EUROPE			
J.L.	8	JP 08-129360 (w/ English abstract)	05/1996	JAPAN			
J.L.	9	EP 0 717 439 A2	06/1996	EUROPE			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
J.L.	10	Lewis A. O. et al.: "Polysilicon TFT Circuit Design and Performance", IEEE Journal of Solid-State Circuits, IEEE Inc. New York, US, Vol. 27, No. 12, 1 December 1992					
J.L.	11	Lewis A. O. et al.: "Physical Mechanisms for Short Channel Effects in Polysilicon Thin Film Transistors", Proceedings of the International Electron Devices Meeting. Washington, Dec. 3-6, 1989, New York, IEEE, US					
EXAMINER <i>Chau Nguyen</i>				DATE CONSIDERED 6-9-05			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: October 24, 2003

17-24-03

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		RULE 53(b) DIVISION OF APPLICATION NO. 10/267,834	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Takuroh OZAWA et al.			
				FILING DATE July 24 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
J.L.		5,714,838	2-1998	HAIGHT et al.			
		6,072,450	6-2000	YAMADA et al.			
		5,587,329	12-96	HSEUH et al.			
		5,828,429	10-98	TAKEMURA			
		6,023,307	02-00	TAKEMURA			
		5,670,792	09-97	UTSUGI et al.			
		6,011,529	01-00	IKEDA			
		5,995,073	11-99	ISAMI et al.			
		6,243,069	06-01	OGAWA et al.			
J.Y.		5,869,929	02-99	EIDA et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
J.L.		EP-A1-0 653 741	05-95	Europe			
		JP-A-8-129358	05-96	Japan			
		JP 8-227276	09-96	Japan			
		JP 08 241057 A	09-96	Japan			
		EP 0112 700 A	07-84	Japan			
		WO 96 06456 A	02-96	WIPO			
		JP 08 129360 A	05-96	Japan			
		EP 0717 439 A	06-96	Europe			
J.L.		JP 08-241057 (translation only)	9-96	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
J.L.		Alan G. Lewis, et al., <u>Physical Mechanisms For Short Channel Effects In Polysilicon Thin Film Transistors</u> , IEEE, 1989, pgs. 13.4.1-13.4.4					
J.L.		Alan G. Lewis et al., <u>Polysilicon TFT Circuit Design and Performance</u> , IEEE Journal of Solid-State Circuits, December 1992, Vol. 27, No. 12, pgs. 1833-1842.					
EXAMINER <i>Jean Desjardins</i>					DATE CONSIDERED 6-9-05		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 24, 2003



Sheet 1 of 1

Form PTO-1449  
(REV. 1/06)U.S. Dept. of Commerce  
PATENT & TRADEMARK OFFICEATTY DOCKET NO.  
100629.03APPLICATION NO.  
10/625,617

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)  
Tokuroh OZAWA et al.FILING DATE  
July 24, 2003GROUP  
2629

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)
J.L.	1	T.P. BRODY, "A 6 x 6-in 20-lpi Electroluminescent Display Panel," <u>IEEE Transactions of Electron Devices</u> , Vol. 22, No. 9, September 1975.

EXAMINER

*Dean* *Myer*

DATE CONSIDERED

7/14/06

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: May 26, 2006

Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		APPLICATION NO. 10/625,617	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Tokuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP 2629	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
J.L.	1	US 4,087,792	5-2-1978	ASARS			
J.L.	2	US 5,296,847 A	3-22-1994	TAKEDA et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
J.L.	3	JP U 62-41193	3-12-1987	JAPAN			
J.L.	4	JP A 02-157815	6-18-1990	JAPAN	X		
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER				DATE CONSIDERED			
				7/14/06			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: May 9, 2006